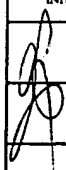
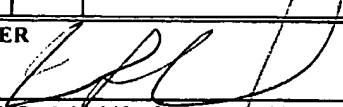
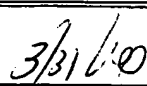


LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)				ATTY. DOCKET NO.:		APPLICATION NO.:		
				4717-13000		10/827,437		
				APPLICANT:				
				Takeshi AKATSU				
				FILING DATE:		GROUP:		
				April 20, 2004		1765		
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							YES	NO
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

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				4717-13000		Not yet assigned	
				APPLICANT:			
				Takeshi AKATSU <i>et al.</i>			
				FILING DATE:		GROUP:	
				Filed concurrently herewith			
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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	AK						
	AL						
	AM						
	AN						
	AO						
	AP						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AQ						
	AR						
	AS						
	AT						
EXAMINER 				DATE CONSIDERED 			
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